

Notice of References Cited	Application/Control No. 10/726,786		Applicant(s)/Patent Under Reexamination JALADANKI ET AL.	
	Examiner Brian P. Whipple		Art Unit 2152	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,194,484 B2	03-2007	Aoki, Norihiro Edwin	707/104.1
*	B	US-6,769,002 B2	07-2004	Ayan, Jordan E.	707/104.1
*	C	US-2004/0260778 A1	12-2004	Banister et al.	709/206
*	D	US-7,219,131 B2	05-2007	Banister et al.	709/206
*	E	US-2004/0044734 A1	03-2004	Beck, Mark	709/206
*	F	US-2002/0103932 A1	08-2002	Bilbrey et al.	709/245
*	G	US-2005/0114453 A1	05-2005	Hardt, Dick C.	709/206
*	H	US-2003/0200265 A1	10-2003	Henry, Steven G.	709/206
*	I	US-7,117,528 B1	10-2006	Hyman et al.	726/5
*	J	US-6,438,583 B1	08-2002	McDowell et al.	709/206
*	K	US-2002/0143879 A1	10-2002	Sommerer, Peter	709/206
*	L	US-6,694,353 B2	02-2004	Sommerer, Peter	709/206
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.